

N-Channel Enhancement Mode Power MOSFET

Description

The PT FGED \blacksquare S uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

- V_{DS} =30V, I_D =120A $R_{DS(ON)}$ <3.5m Ω @ V_{GS} =10V (Typ:3.0m Ω)
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

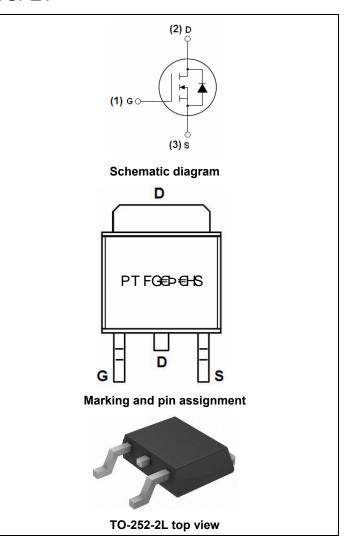
Application

- Power switching application
- Hard switched and high frequency circuits

Uninterruptible power supply

100% UIS TESTED!

100% ΔVds TESTED!



Package Marking And Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity	
PT FG€Þ€HS	PT FG€Þ€HS	TO-252-2L	_	-	-	

Absolute Maximum Ratings (T_A=25 ℃ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	30	V
Gate-Source Voltage	V _{GS}	±20	V
Drain Current-Continuous	I _D	120	Α
Drain Current-Continuous(T _C =100°C)	I _D (100℃)	84	Α
Pulsed Drain Current	I _{DM}	400	Α
Maximum Power Dissipation	P _D	120	W
Single pulse avalanche energy (Note 5)	E _{AS}	350	mJ
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55 To 175	$^{\circ}$



Thermal Characteristic

Thermal Resistance, Junction-to-Case(Note 2)	R _{θJC} 1.25	°C/W	
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Electrical Characteristics (T_A=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics			•			
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	30	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =30V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =250μA	1	1.6	3	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =20A	-	3.0	3.5	mΩ
Forward Transconductance	g FS	V _{DS} =10V,I _D =20A	50	-	-	S
Dynamic Characteristics (Note4)	·					
Input Capacitance	C _{lss}	\/ -25\/\/ -0\/		3550		PF
Output Capacitance	C _{oss}	V_{DS} =25V, V_{GS} =0V, F=1.0MHz		1350		PF
Reverse Transfer Capacitance	C _{rss}	F-1.UIVINZ		120		PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t _{d(on)}		-	11	-	nS
Turn-on Rise Time	tr	VGS=10V,VDS=20V	-	10	-	nS
Turn-Off Delay Time	$t_{d(off)}$	RL=0.75 Ω ,RGEN=3 Ω	-	38	-	nS
Turn-Off Fall Time	t _f		-	11	-	nS
Total Gate Charge	Q_g			48		nC
Gate-Source Charge	Q_{gs}	VGS=10V,VDS=15V,ID=20A		11		nC
Gate-Drain Charge	Q_{gd}			10		nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V_{SD}	V _{GS} =0V,I _S =20A	-	-	1.2	V
Diode Forward Current (Note 2)	Is	-	-	-	120	Α
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF = 20A	-	21	-	nS
Reverse Recovery Charge	Qrr	di/dt = 100A/μs(Note3)	-	58	-	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

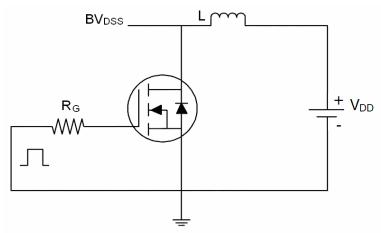
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.

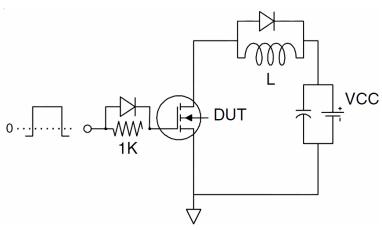
- **4.** Guaranteed by design, not subject to production
- **5.** EAS condition: Tj=25 $^{\circ}$ C,V_{DD}=15V,V_G=10V,L=0.5mH,Rg=25 Ω

Test circuit

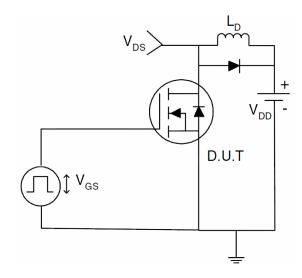
1) E_{AS} test Circuits



2) Gate charge test Circuit:



3) Switch Time Test Circuit:



Typical Electrical and Thermal Characteristics (Curves)

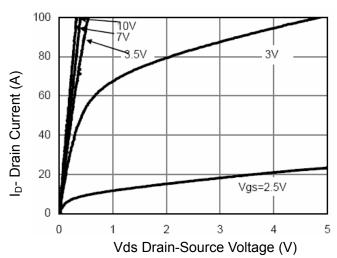


Figure 1 Output Characteristics

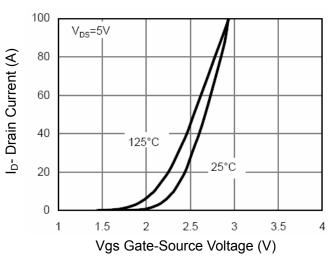


Figure 2 Transfer Characteristics

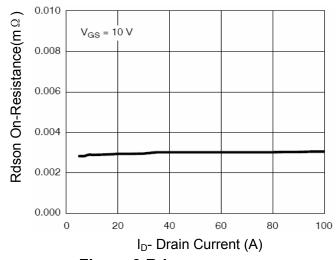


Figure 3 Rdson- Drain Current

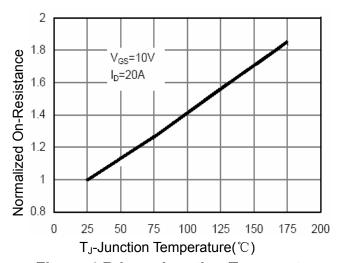


Figure 4 Rdson-Junction Temperature

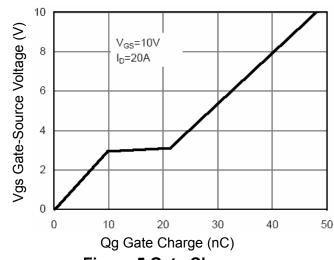


Figure 5 Gate Charge

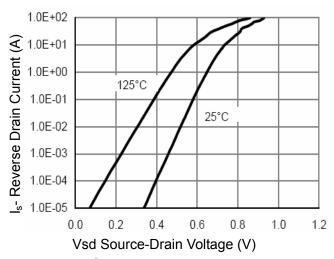


Figure 6 Source- Drain Diode Forward

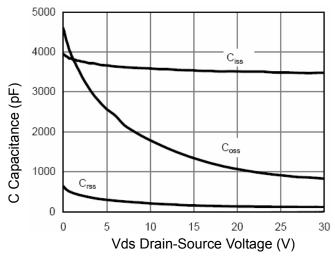
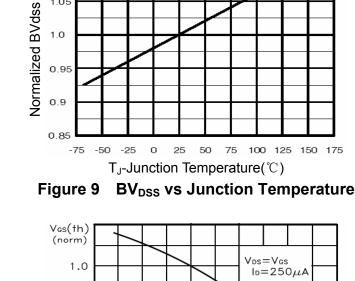
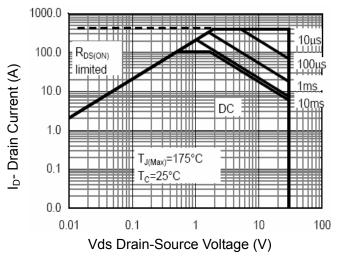


Figure 7 Capacitance vs Vds



1.1

1.05



Safe Operation Area

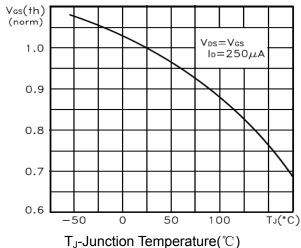


Figure 10 V_{GS(th)} vs Junction Temperature

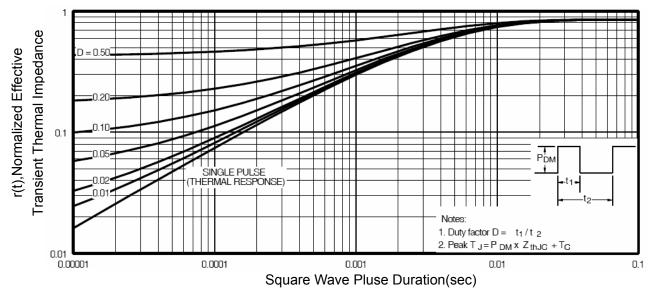
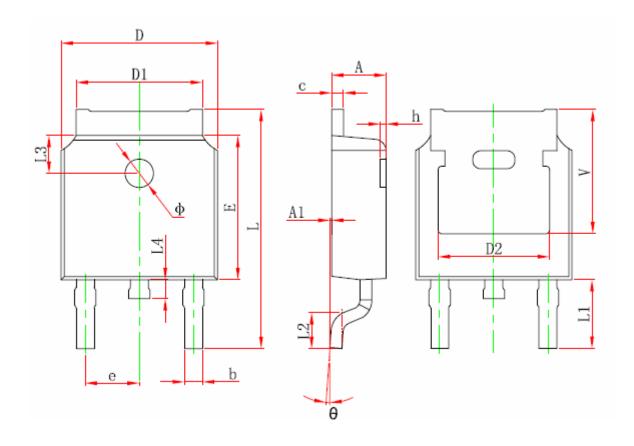


Figure 11 Normalized Maximum Transient Thermal Impedance

TO-252-2L Package Information



Cumbal	Dimensions	In Millimeters	Dimensions In Inches			
Symbol	Min.	Max.	Min.	Max.		
Α	2.200	2.400	0.087	0.094		
A1	0.000	0.127	0.000	0.005		
b	0.660	0.860	0.026	0.034		
С	0.460	0.580	0.018	0.023		
D	6.500	6.700	0.256	0.264		
D1	5.100	5.460	0.201	0.215		
D2	4.830	REF.	0.190 REF.			
E	6.000	6.200	0.236	0.244		
е	2.186	2.386	0.086	0.094		
L	9.800	10.400	0.386	0.409		
L1	2.900	REF.	0.114 REF.			
L2	1.400	1.700	0.055	0.067		
L3	1.600	REF.	0.063 REF.			
L4	0.600	1.000	0.024	0.039		
Ф	1.100	1.300	0.043	0.051		
θ	0°	8°	0°	8°		
h	0.000	0.300	0.000	0.012		
V	5.350 REF.			REF.		

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